

TER Series Electric Resistance Measuring Instrument for Metals and Semiconductors

For phase transformation, aging and recrystallization reaction of metals

This system permits precision measurement of the electric resistance of metal alloys and semiconductors by the d. c. 4-terminal method.

•Application

1. Research on phase transformation, age precipitation, recrystallization and others of metals
2. Analysis of recrystallization of amorphous metals
3. R & D of shape memory metals
4. Measurement of temperature vs. electric resistance of semiconductor materials

•Features

1. Measurement of electric resistance in a constant rate heating process and a constant temperature holding process.
2. High accuracy measurement by the d. c. 4-terminal method
3. Measurement is not affected by thermal emf.

•Specifications

Temperature range	①-150 to 200℃ ②room temperature to maximum 1400℃
Measuring system	d. c. 4-terminal method
Measurement range	100Ωto 5×10 ⁻⁵ Ω
Sample mount	10mm dia. × 100 mm
Measurement atmosphere	Inert gas, air, vacuum (option)

